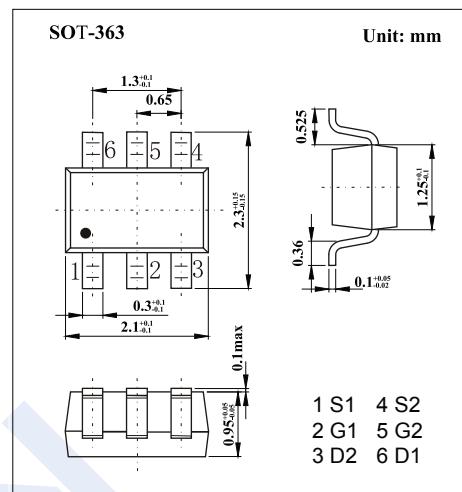
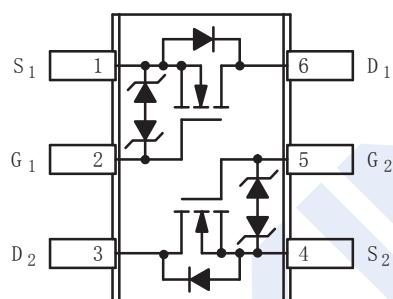


Dual N-channel MOSFET

2KK5077

■ Features

- $BV_{DSS} = 60\text{ V}$
 - $I_D = 295\text{ mA}$
 - $R_{DS(ON)} \leq 1.8\Omega @ V_{GS} = 10\text{ V}$
 - $R_{DS(ON)} \leq 2.5\Omega @ V_{GS} = 4.5\text{ V}$
 - Low RDS(on)
 - Low Gate Threshold
 - Low Input Capacitance
 - ESD Protected Gate



■ Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise stated)

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V _{DS}	60	V	
Gate-Source Voltage	V _{GS}	±20		
Continuous Drain Current	Steady State	I _D	mA	
	t ≤ 5 s			
Pulsed Drain Current	t _p = 10 µs	I _{DM}	900	°C/W
Thermal Resistance, Junction- to-Ambient ^(Note 1)	R _{θJA}	467		
Gate-Source ESD Rating (HBM)	ESD _{HBM}	2000	V	
Gate-Source ESD Rating (MM)	ESD _{MM}	200		
Power Dissipation	Steady State	P _D	mW	
	t ≤ 5 s			
Junction Temperature	T _J	150	°C	
Storage Temperature Range	T _{stg}	-55 to 150		

Note 1. Surface mounted on FR4 board using 1 in sq pad size, (Cu area = 1.127 in sq [2 oz] including traces).

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■ Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
OFF Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 250 \mu\text{A}, V_{GS} = 0\text{V}$	60			V
Zero Gate Voltage Drain Current	$I_{DS(on)}$	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$		1		μA
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$		500		
Gate to Source Leakage Current	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 10	
ON Characteristics (Note 2)						
Gate to Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0		2.5	V
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	$V_{GS} = 10 \text{ V}, I_D = 500 \text{ mA}$			1.8	Ω
		$V_{GS} = 4.5 \text{ V}, I_D = 200 \text{ mA}$			2.5	
Charges and Capacitances						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 20 \text{ V}, f = 1 \text{ MHz}$		26		pF
Output Capacitance	C_{oss}			4.4		
Reverse Transfer Capacitance	C_{rss}			2.5		
Total Gate Charge	$Q_{G(\text{TOT})}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 25 \text{ V}, I_D = 200 \text{ mA}$		0.9		nC
Threshold Gate Charge	$Q_{G(\text{TH})}$			0.2		
Gate Source Charge	Q_{gs}			0.3		
Gate Drain Charge	Q_{gd}			0.28		
Switching Characteristics (Note 3)						
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 25 \text{ V}, I_D = 200 \text{ mA}, R_G = 25 \Omega$		22		ns
Turn-On Rise Time	t_r			34		
Turn-Off Delay Time	$t_{d(off)}$			34		
Turn-Off Fall Time	t_f			32		
Drain-Source Diode Characteristics						
Diode Forward Voltage	V_{SD}	$V_{GS} = 0 \text{ V}, I_S = 200 \text{ mA}$		0.8	1.2	V

Notes:

2. Pulse Test: pulse width $\leq 300 \text{ s}$, duty cycle $\leq 2\%$.
3. Switching characteristics are independent of operating junction temperatures.

■ Marking

Marking	KAR
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Dual N-channel MOSFET

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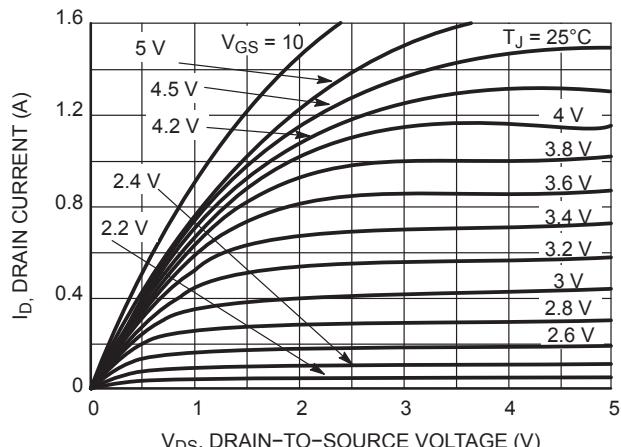
■ Typical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Figure 1. On-Region Characteristics

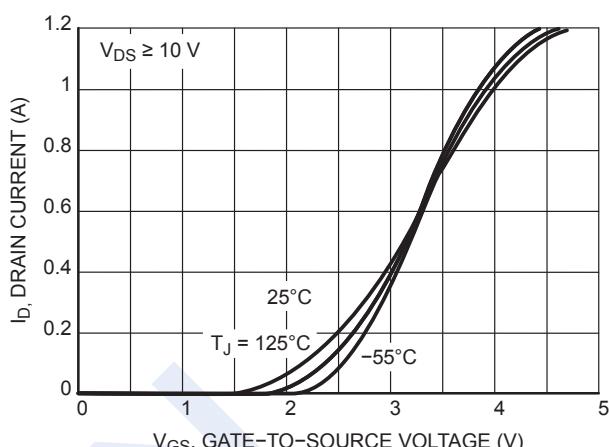


Figure 2. Transfer Characteristics

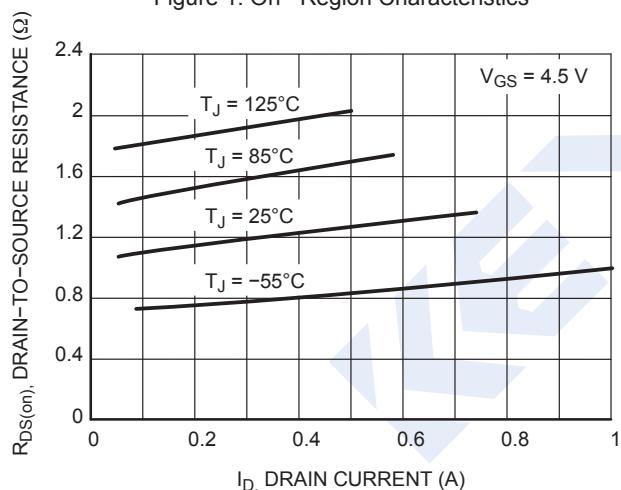


Figure 3. On-Resistance vs. Drain Current and Temperature

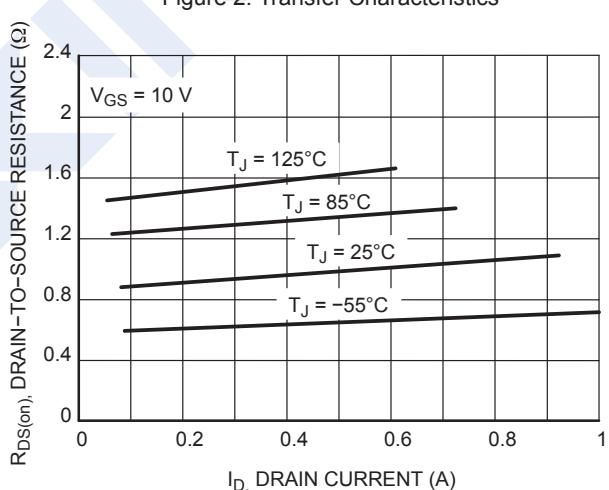


Figure 4. On-Resistance vs. Drain Current and Temperature

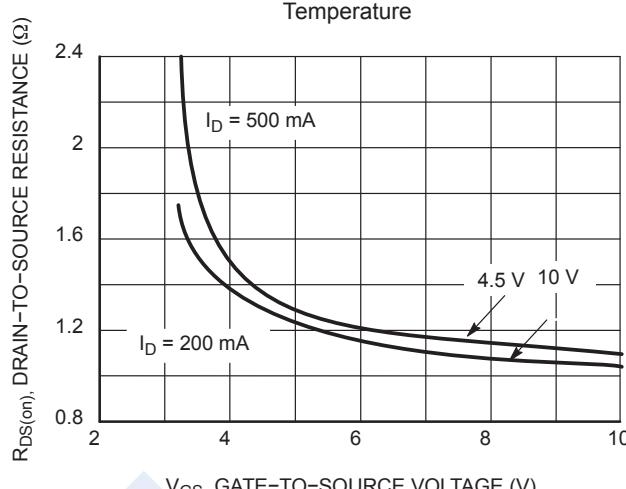


Figure 5. On-Resistance versus Gate-to-Source Voltage

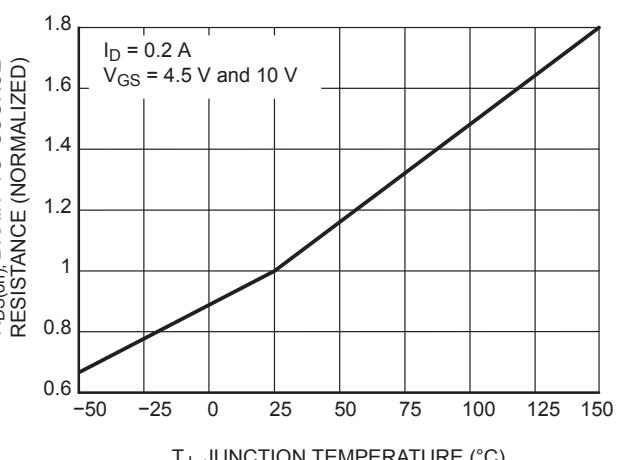


Figure 6. On-Resistance Variation with Temperature

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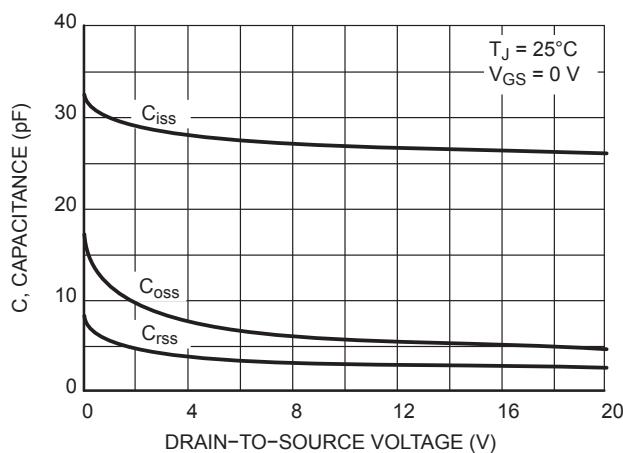


Figure 7. Capacitance Variation

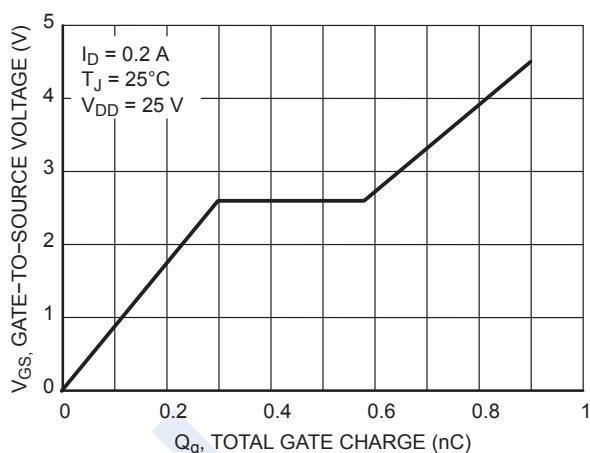


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

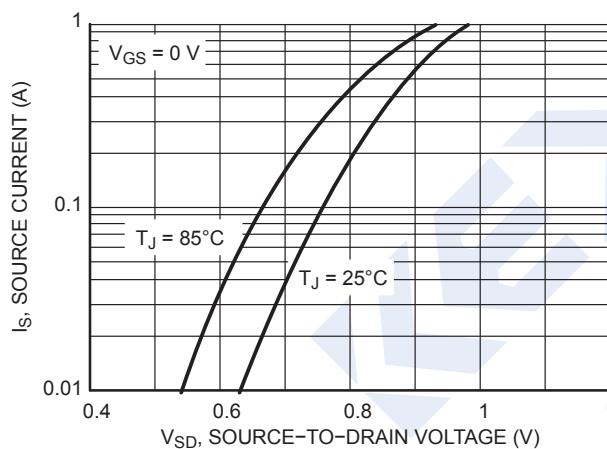


Figure 9. Diode Forward Voltage vs. Current

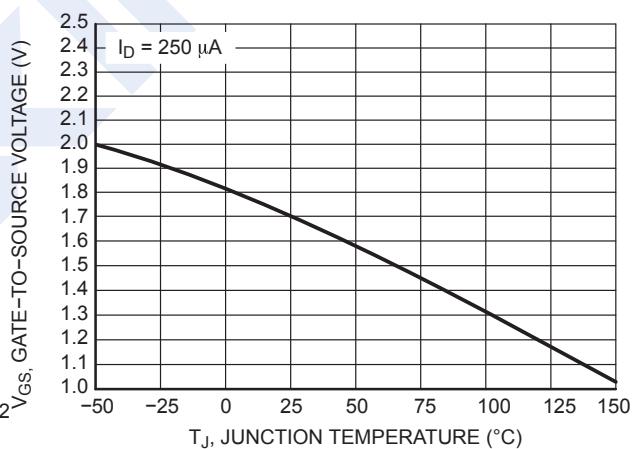


Figure 10. Threshold Voltage with Temperature

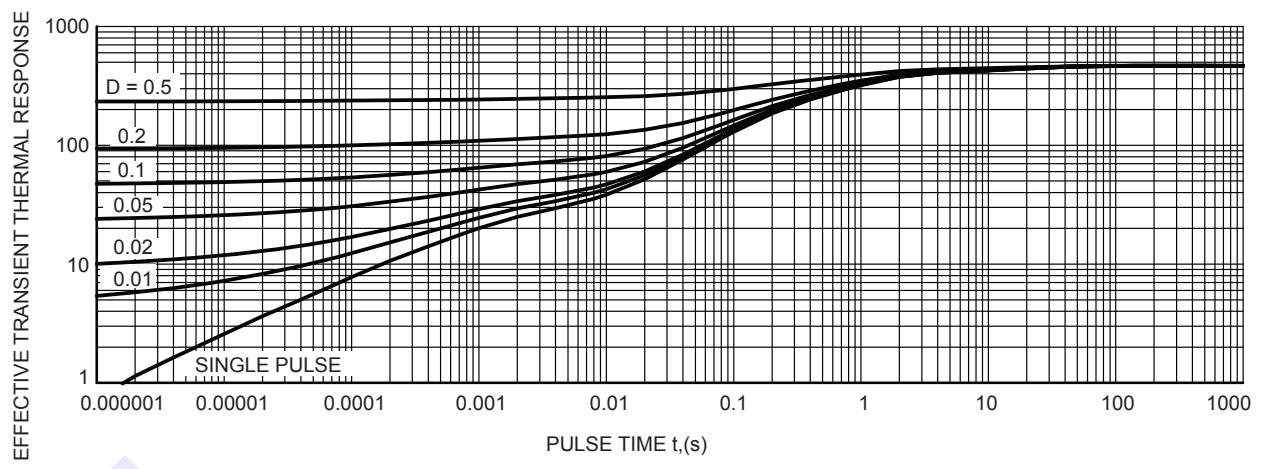


Figure 11. Thermal Response